

# Integrated Circuit Costs

Last updated 1/18/24

A faded, light-colored image of an integrated circuit chip is visible in the background of the lower half of the slide. The chip shows a complex grid of circuitry with various colored regions in shades of yellow, blue, and brown.

# Integrated Circuit Costs

- Processor Cost Overview
  - Key Components building to part cost
    - Wafer Cost
      - 300mm wafers range from \$5000/wafer (early) down to \$1200/wafer (mature)
      - Cost reductions associated with process maturity
      - Wafer Yield = number of wafers that make it through the process with working transistors
    - Die Cost
      - Based on the number of full die that can fit on a wafer
    - Good Die Cost
      - Based on the number of die that are fully functional (may include redundancy)
    - Packaged Part Cost
      - Add the cost of package and packaging process
    - Good Packaged Part Cost
      - Based on the number of fully functional packaged parts (may include redundancy)
    - Margin
      - Additional \$ to cover R&D, facilities, ... AND profit

# Integrated Circuit Costs

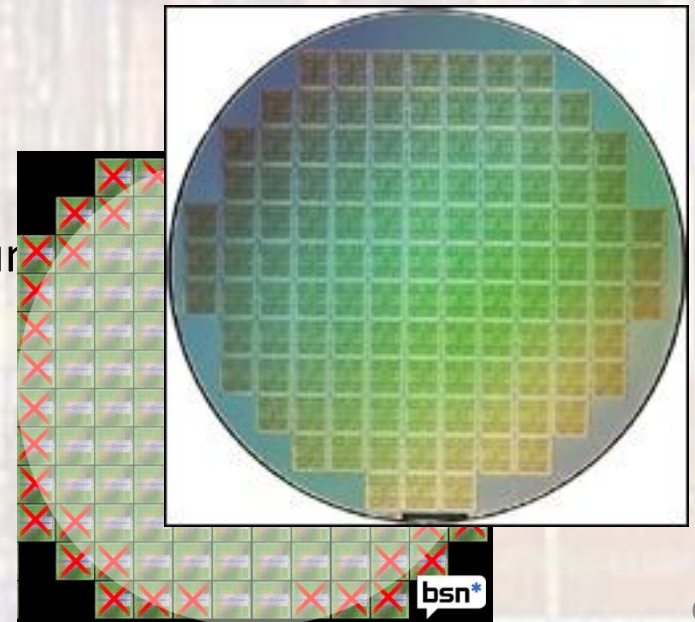
- Processor Cost Overview

- Wafer Cost

- 45nm, 300mm wafers ~ \$2000/wafer
- Typical “lot” of 25 wafers
- Typical wafer yield of 95%
  - Losses are a combination of single wafers and whole lots

- Die Cost

- # of full die that will fit on a wafer
- Various approaches to maximize die count
- Die Cost = Wafer Cost / # of Die



# Integrated Circuit Costs

- Processor Cost Overview



Apple intel Ad.mp4

# Integrated Circuit Costs

- Processor Cost Overview
  - Good Die Cost
    - Based on the number of die that are fully functional
    - 2 primary yield components
      - Parametric Yield
      - Process Yield
  - Parametric Yield
    - Parts that fail to meet a performance measure
    - Typically max frequency or current drain
    - Can be mitigated by binning (have a fast version of the part and a slow version)
    - Typically 95% on digital parts
  - Process Yield
    - Dominated by defects in the manufacturing process
    - $Y = Y_0 \left(1 + \frac{D_0 A}{\alpha}\right)^{-\alpha}$  NB - negative binomial model
    - $Y_0$  – portion of area subject to defects (0.8-0.95)
    - $D_0$  – defect density (100defects/cm<sup>2</sup> (early) – 0.15defects/cm<sup>2</sup>(mature))
    - $A$  - die area (20mm<sup>2</sup> – 400mm<sup>2</sup>)
    - $\alpha$  - cluster factor (10 – 20)

# Integrated Circuit Costs

- Processor Cost Overview
  - Packaged Part Cost
    - Add the cost of package and packaging process
    - \$0.20 for small simple packages
    - \$2 - \$4 for complex BGAs
    - \$1 for POP
  - Good Packaged Part Cost
    - Based on the number of fully functional packaged parts
    - Package yield is typically 95% - 99+%
  - Margin
    - Additional \$ to cover R&D, facilities, ... AND profit
    - 20% for mature products
    - 50% for new products



# Integrated Circuit Costs

- Processor Cost Example

- Wafer Cost

- 300mm, 45nm → \$2000 / wafer
    - Wafer yield – 95% → \$2105 / wafer

- Die Cost

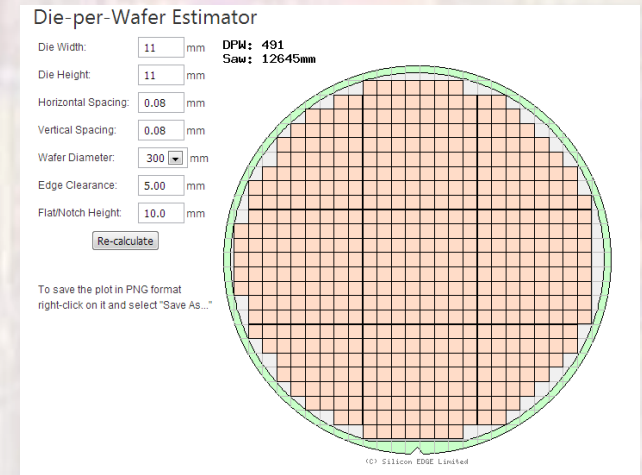
- 122mm<sup>2</sup> → 491 die/wafer → \$4.29 / die

- Good Die Cost

- $$Y = Y_o \left(1 + \frac{D_0 A}{\alpha}\right)^{-\alpha} = 0.95 \left(1 + \frac{(0.25 \text{ defects/cm}^2)(122 \text{mm}^2 \times (\frac{1 \text{cm}}{10 \text{mm}})^2)}{10}\right)^{-10} = 0.703$$
    - Defect driven die cost = \$4.29/die / 0.703 = \$6.10 / die
    - Parametric yield – 0.98 → \$6.22 / die

- Packaged Part Cost

- 1300 pin – POP-BGA = \$3 → 9.22 / part





# Integrated Circuit Costs

- Processor Cost Example
  - Good Packaged Part Cost
    - 98% yield  $\rightarrow$  9.41 / part
  - Margin
    - If this was not an Apple design
      - Margin = 50%  $\rightarrow$  Part cost = \$18.82
    - Apple can cover the margin costs at the final product level
      - $\rightarrow$  Part Cost = \$9.41
  - Gut feel cost before margin = \$6.50